

# DESIGNCON<sup>®</sup> 2013

**JANUARY 28-31, 2013**  
**SANTA CLARA CONVENTION CENTER**



## Innovative PDN Design Guidelines for Practical High Layer-Count PCBs

### Session 11 - WA - 1

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 Bruce Archambeault, Jun Fan and James Drewniak



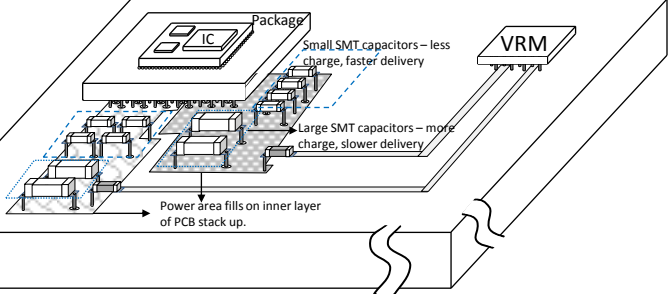




## Motivation

Multiple power nets, each with its own power plane, and decoupling capacitors.

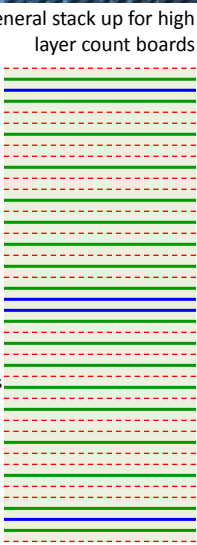
General stack up for high layer count boards



**Critical decisions about the PDN design:**

- Location of capacitors
- Location of power plane in stack up
- Distance of capacitors from the IC
- Location of the return vias and the return planes

- Possible Power Net Locations
- Reference Net
- - - Signal Layer



**How do these choices affect the PDN response?**

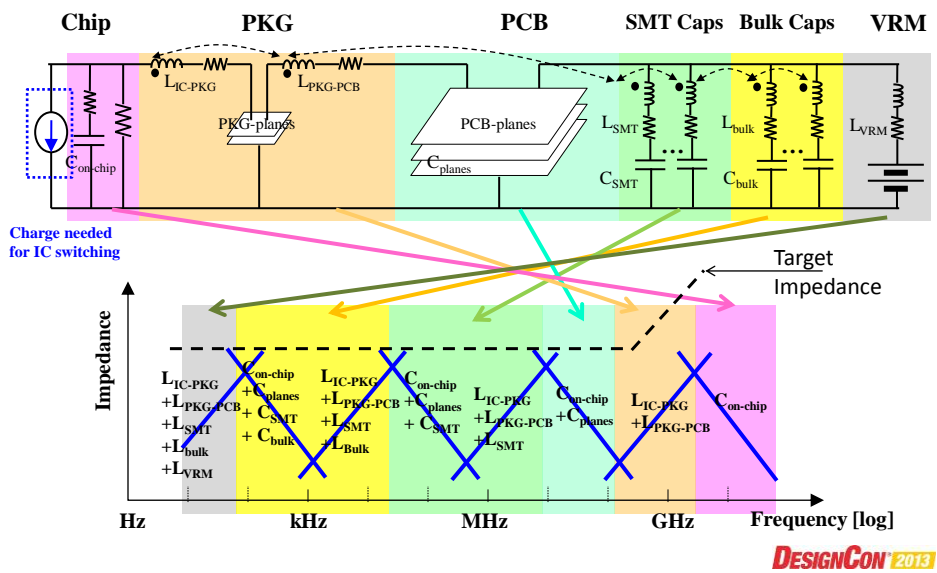
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# Outline

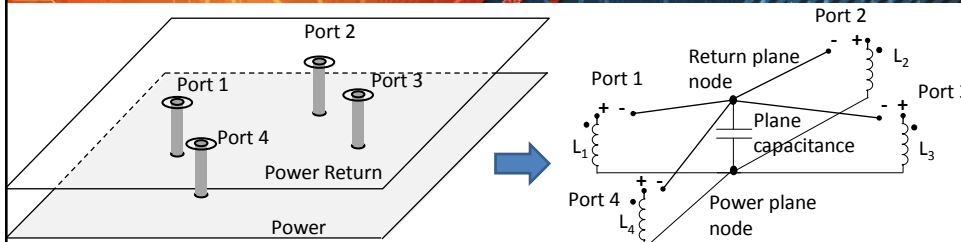
- Physics Based Model for Real PCB PDNs
- $L_{EQ}$  and  $L_{IC}$  using the Geometry – Model – Response Paradigm
- Case Studies for Design Guidelines
- Trends in  $L_{EQ}$  and  $L_{IC}$  with Change PCB Stack Up Thickness
- Conclusions

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# PCB PDN Model and the Asymptotic Impedance Curve



# Equivalent Circuit Model for a Single Cavity



$$L_{ij} = \frac{\mu d}{ab} \sum_{m=0}^{\infty} \sum_{n=0}^{\infty} \frac{\epsilon_m^2 \epsilon_n^2}{k_{mn}^2} f(x_i, y_i, x_j, y_j) \Big|_{(m,n) \neq (0,0)}$$

$$f(x_i, y_i, x_j, y_j) = \cos\left(\frac{m\pi x_i}{a}\right) \sin c\left(\frac{m\pi x_j}{2a}\right) \cos\left(\frac{n\pi y_i}{b}\right) \sin c\left(\frac{n\pi y_j}{2b}\right) \cdot \cos\left(\frac{m\pi x_j}{a}\right) \sin c\left(\frac{m\pi x_i}{2a}\right) \cos\left(\frac{n\pi y_j}{b}\right) \sin c\left(\frac{n\pi y_i}{2b}\right)$$

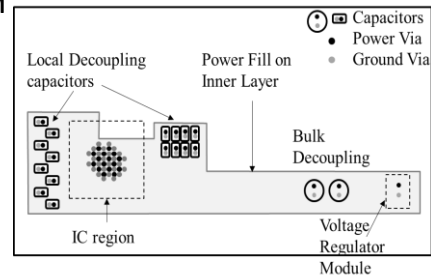
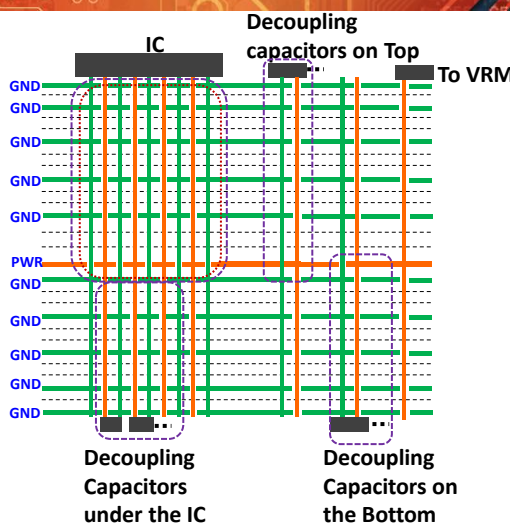
$$k_{mn}^2 = \left(\frac{m\pi}{a}\right)^2 + \left(\frac{n\pi}{b}\right)^2$$

$$\epsilon_m = \begin{cases} \sqrt{2}; m = 0 \\ 1; m \neq 0 \end{cases}$$

Where,  
 $L_{ij}$  : Self or Mutual Inductance between  $i^{th}$  and  $j^{th}$  via  
 $a, b$  : Dimension of the plane in x,y direction,  
 $d$  : Thickness of cavity in the z direction,  
 $m, n$  : Mode numbers in x and y directions  
 $(x_i, y_i)$  : Location of Via i, and  
 $t_{xi}, t_{yi}$  : x and y dimensions of Via i (rectangular).



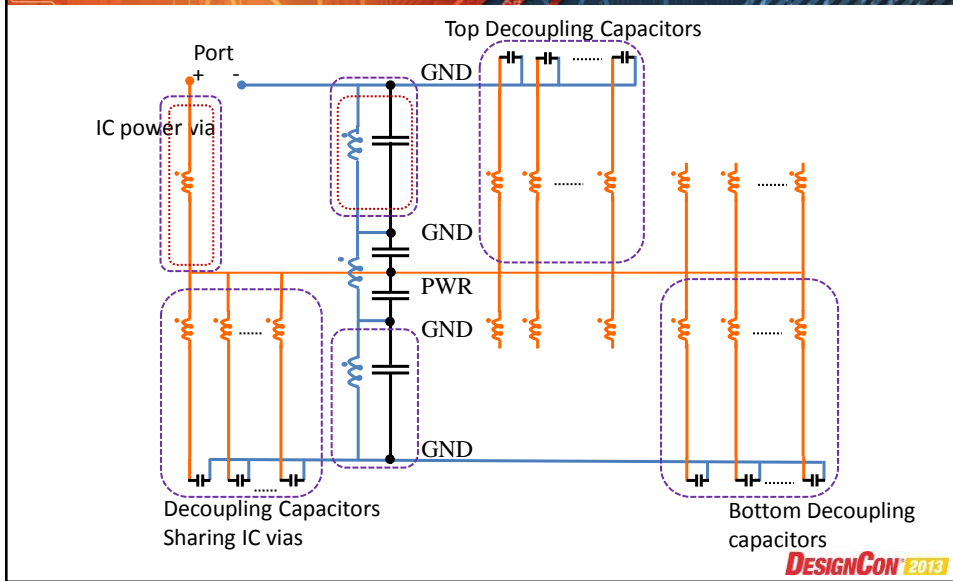
# A Real PCB PDN Geometry



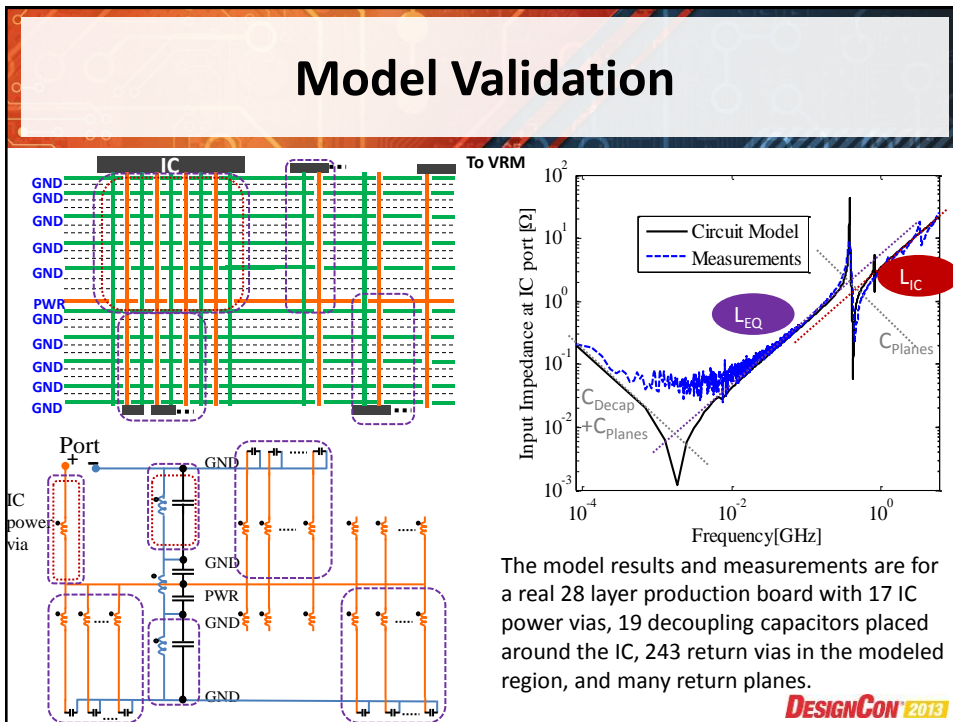
The stack up and layout is used to indicate a real production PCB, with and irregular power fill, many power return planes, many decoupling capacitors and power their power and power return vias.

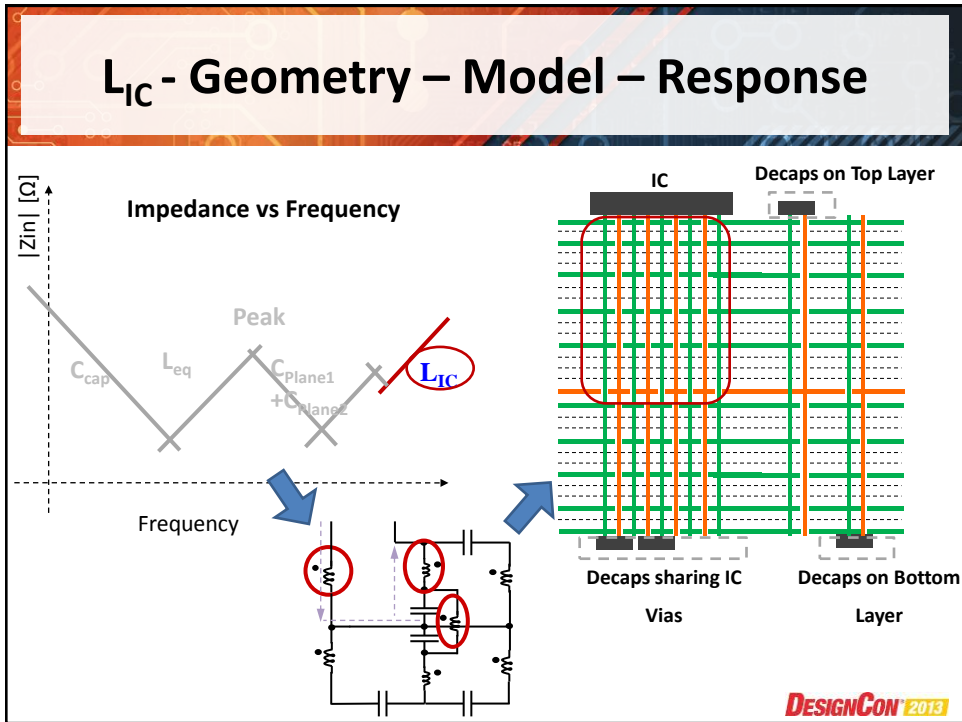
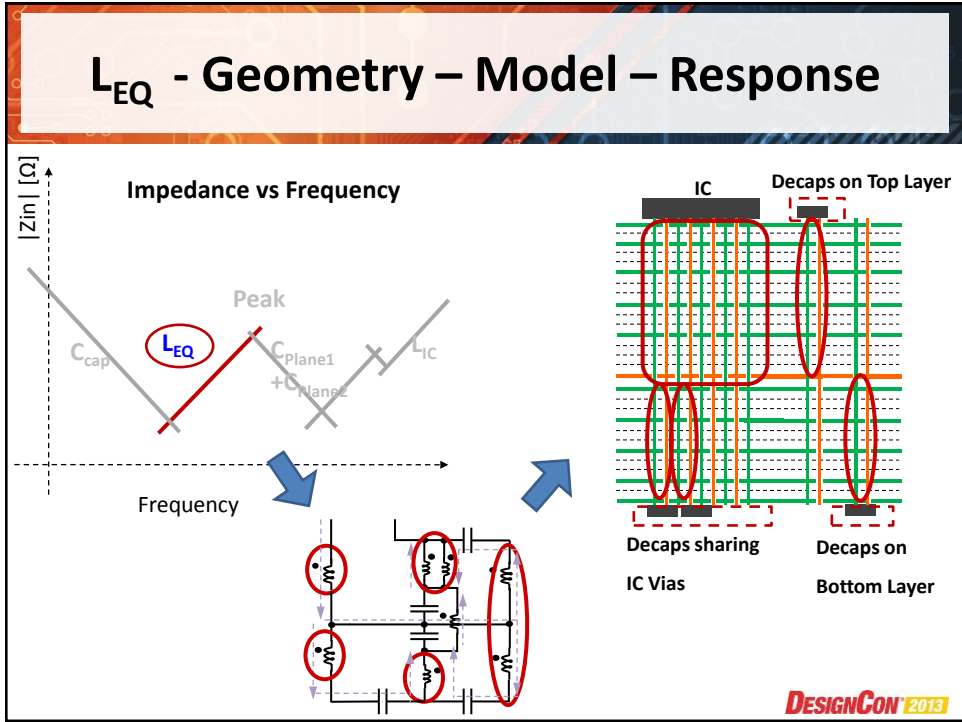


# Equivalent Circuit Model for the Real PCB PDN



# Model Validation



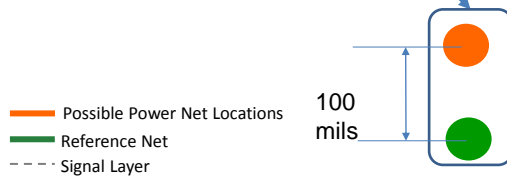
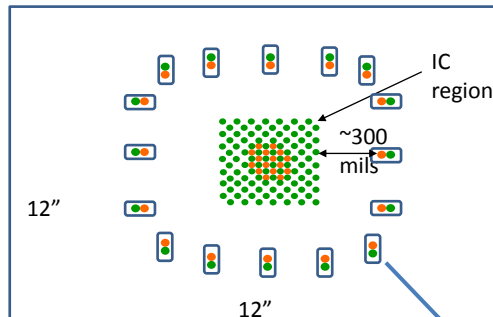
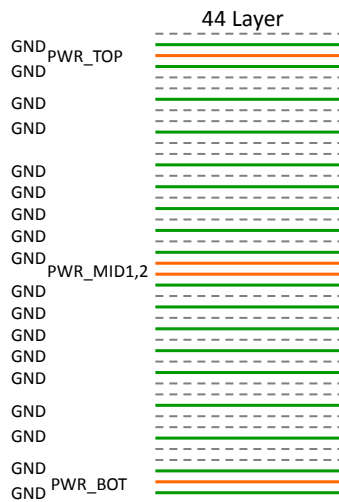


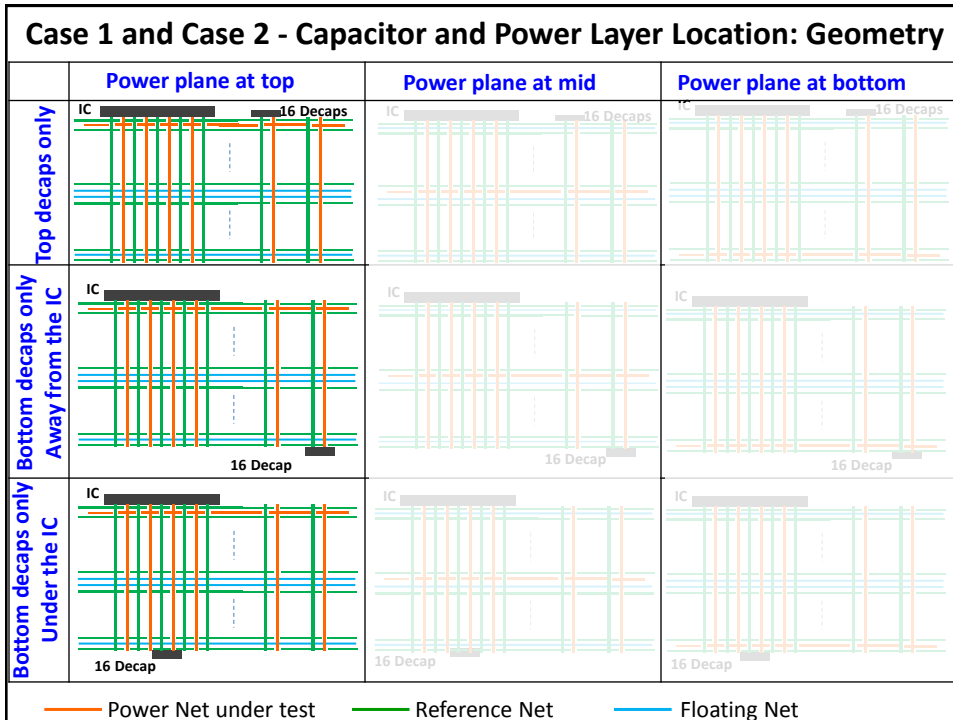
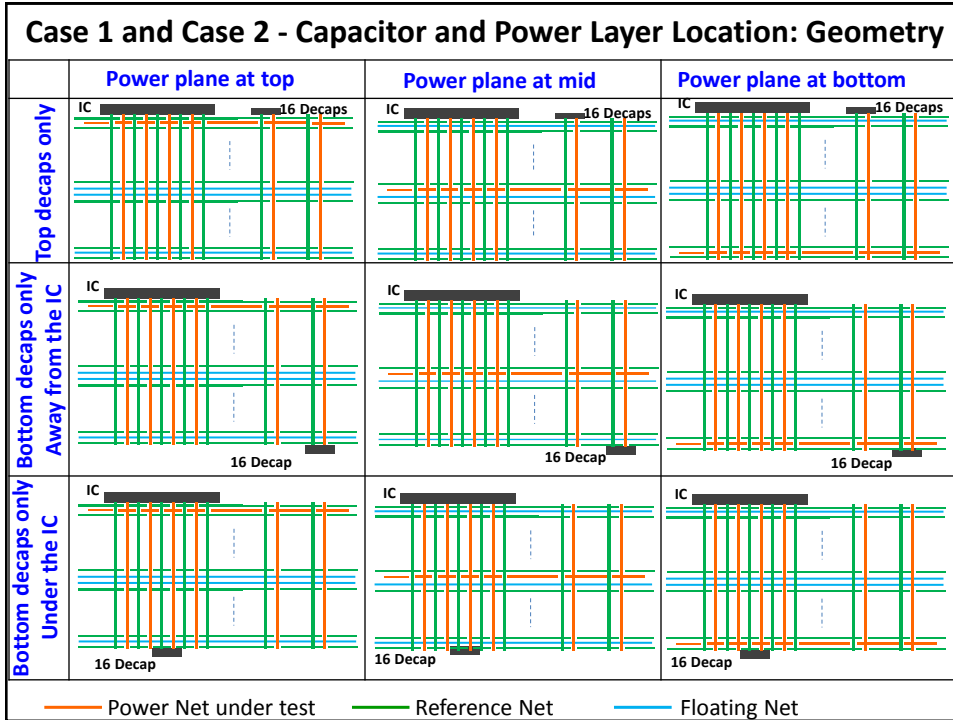
# Case Study Considerations

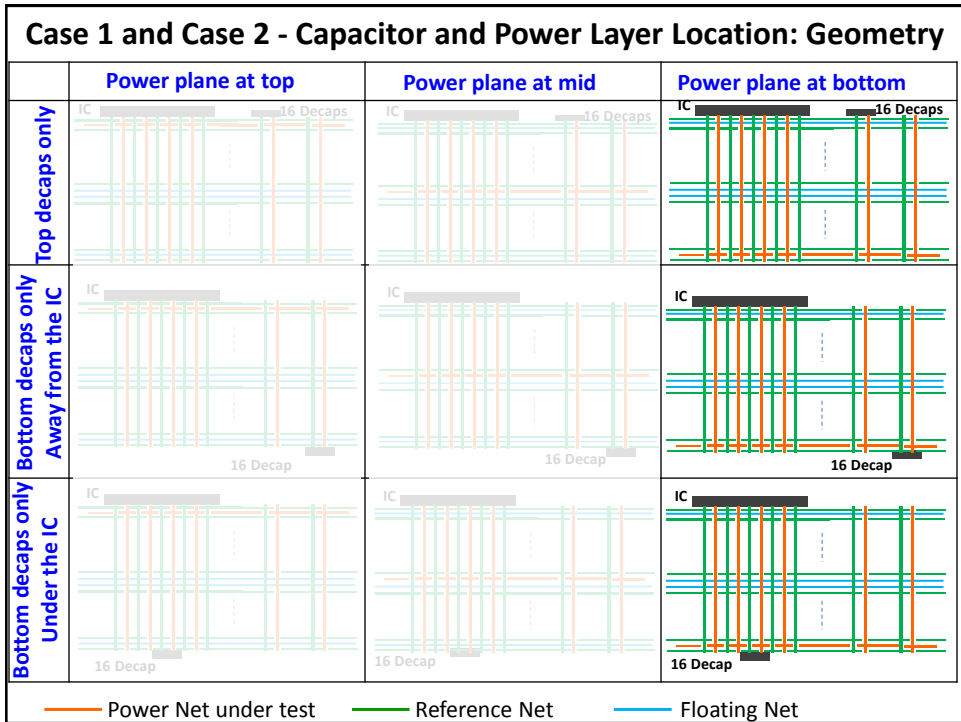
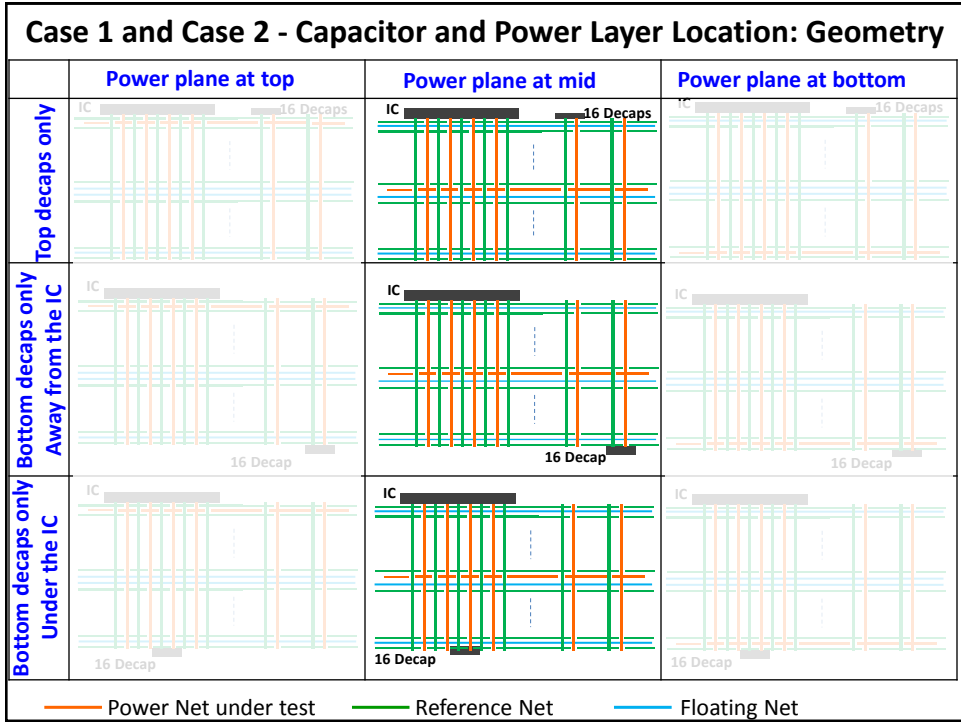
Cases	Variation 1	Variation 2	Variation 3 ...
Capacitor Location	IC 16 Top Capacitors	IC 16 Bottom Capacitors	IC 16 Bottom Capacitors, Under the IC
Capacitor Distance	IC 300 mils 16 Capacitor Ring	IC 0.5" 16 Capacitor Ring	IC 1" 16 Capacitor Ring
Power Plane Location	IC Top Power Layer	IC Middle Power Layer	IC Bottom Power Layer
Return Via for Capacitor	50 mils	100 mils	300 mils
Return Planes	All Return Planes	No Close Return Plane for IC	Only One Closest Return Plane Above Power Plane
			Only One Closest Return Plane Below Power Plane



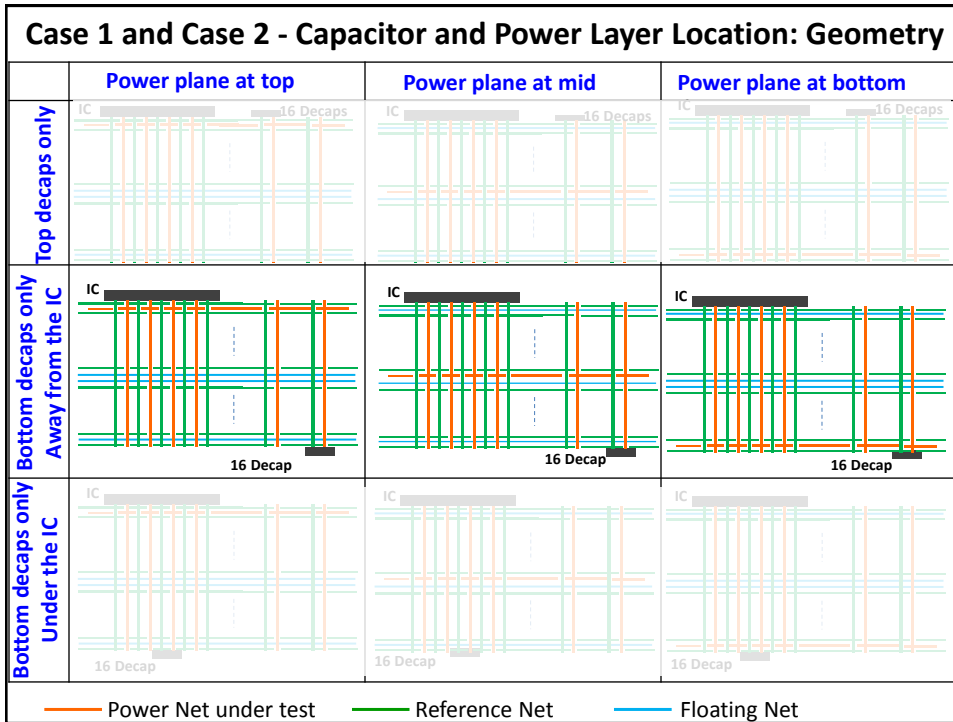
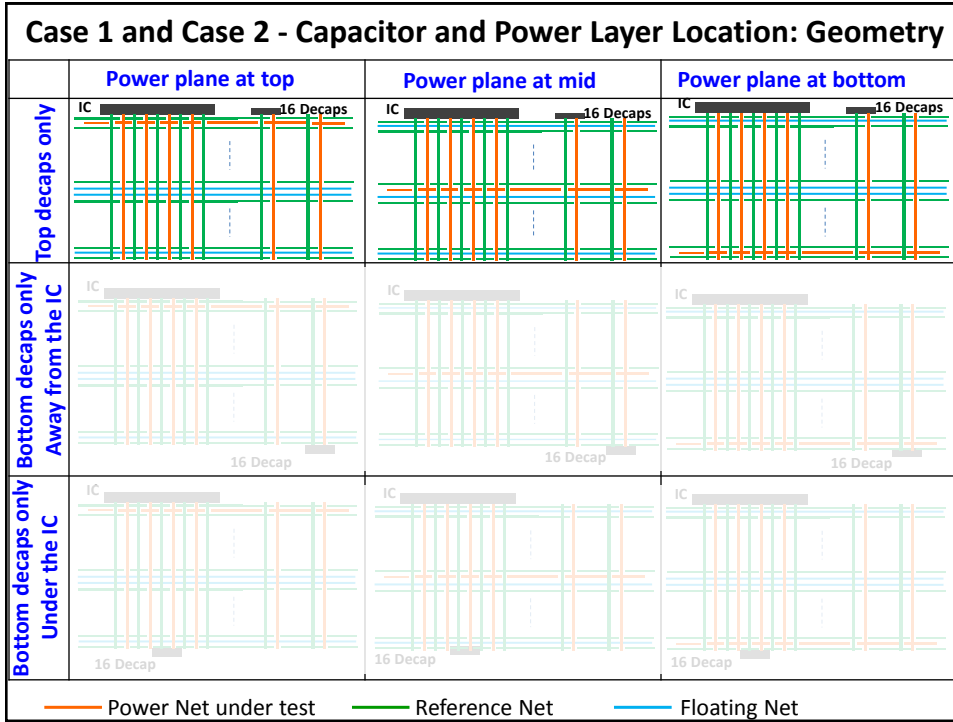
# Stack Up and Layout of the Reference Geometry

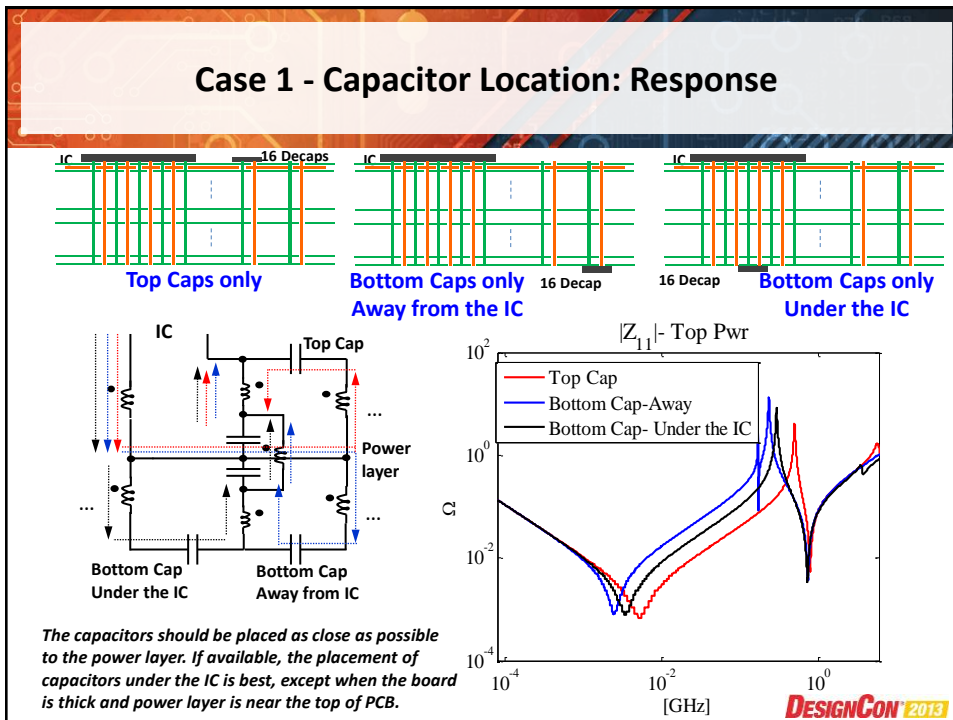
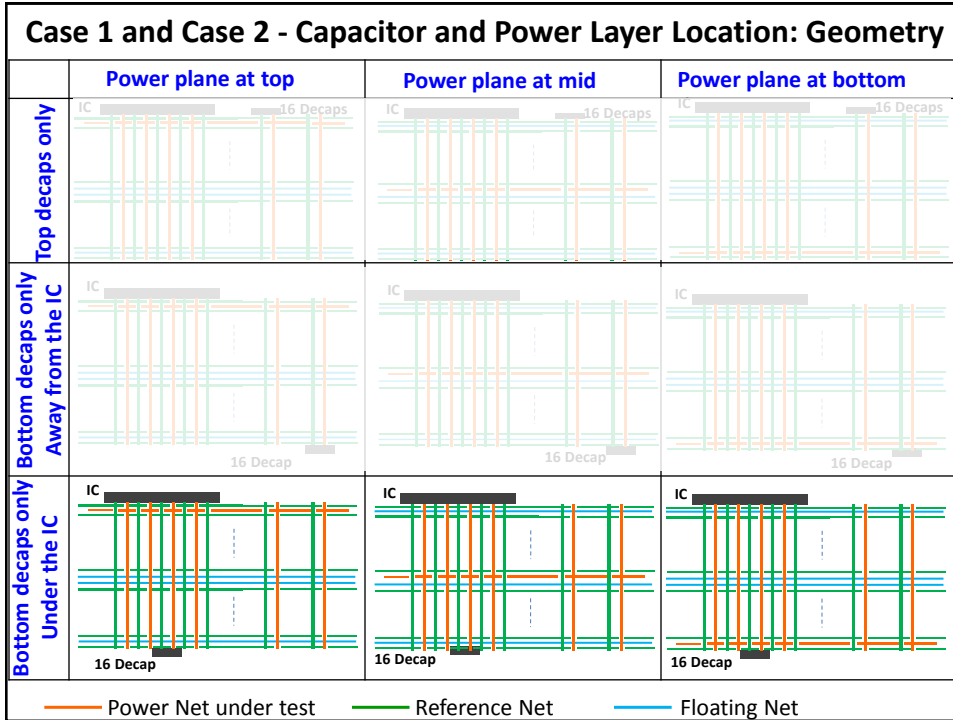




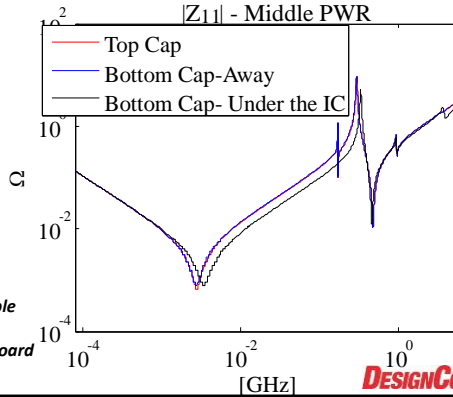
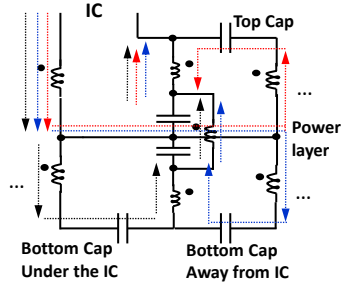
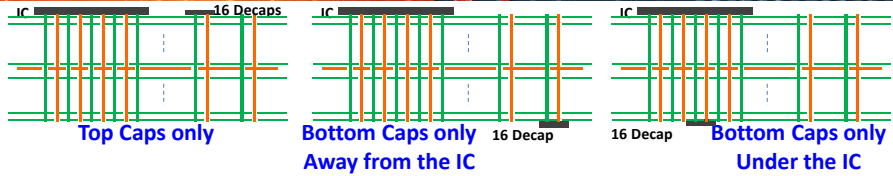








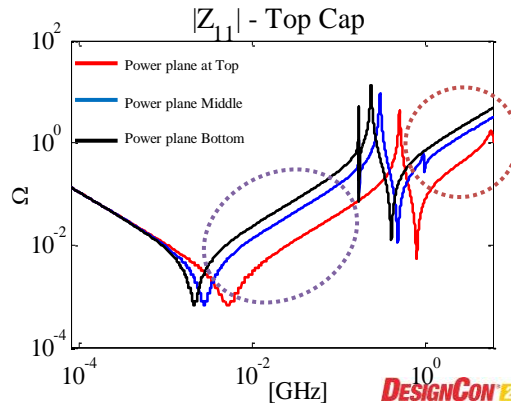
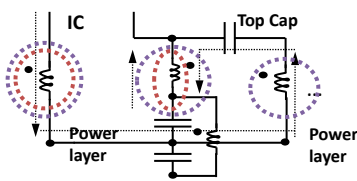
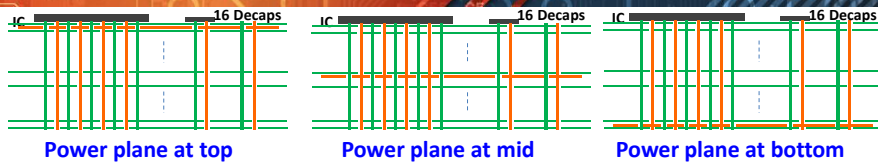
### Case 1 - Capacitor Location: Response



The capacitors should be placed as close as possible to the power layer. If available, the placement of capacitors under the IC is best, except when the board is thick and power layer is near the top of PCB.

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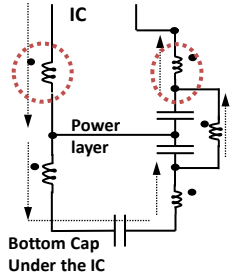
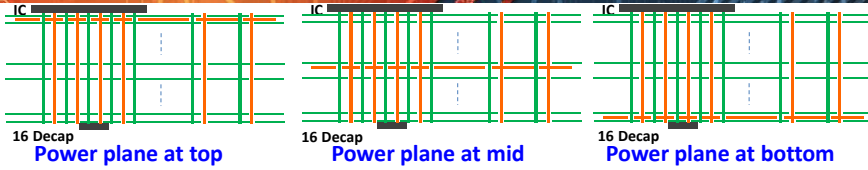
### Case 2 - Power Layer Location: Response



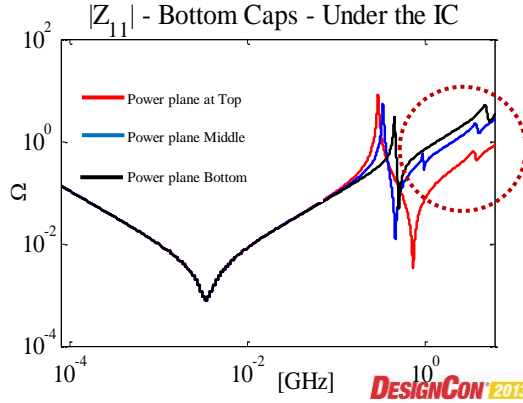
The power layer should be placed as close as possible to the IC.

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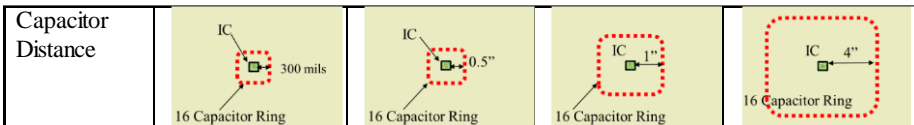
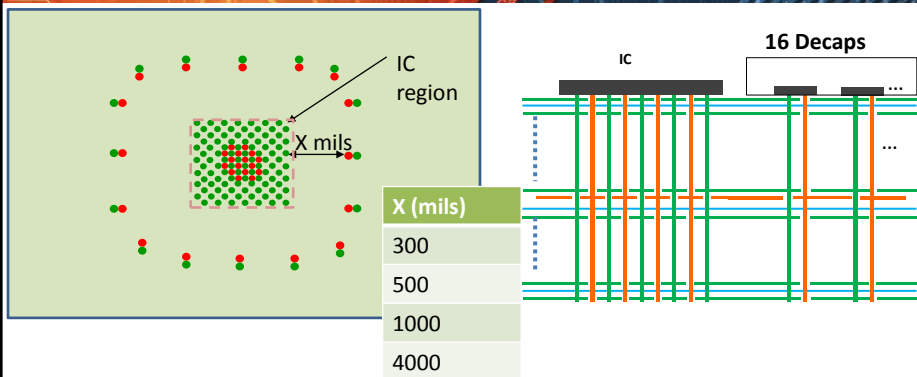
### Case 2 - Power Layer Location: Response



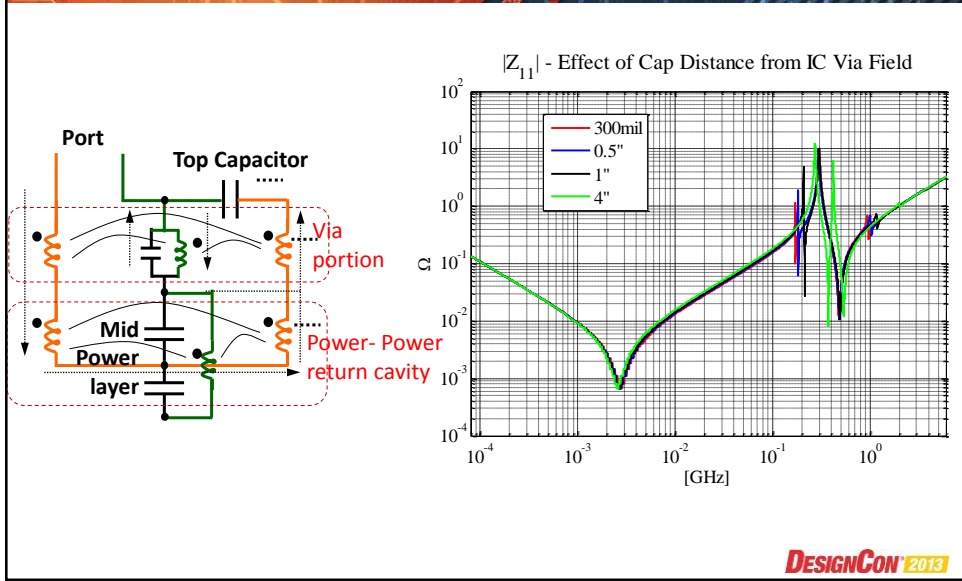
*The power layer should be placed as close as possible to the IC.*



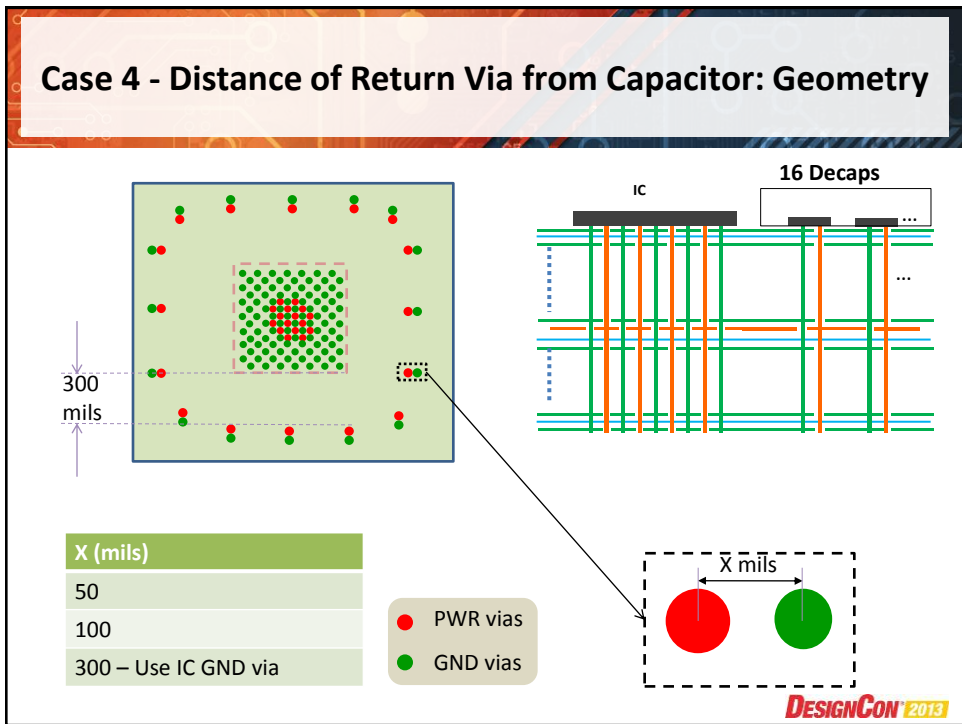
### Case 3 - Distance of Capacitor from IC: Geometry



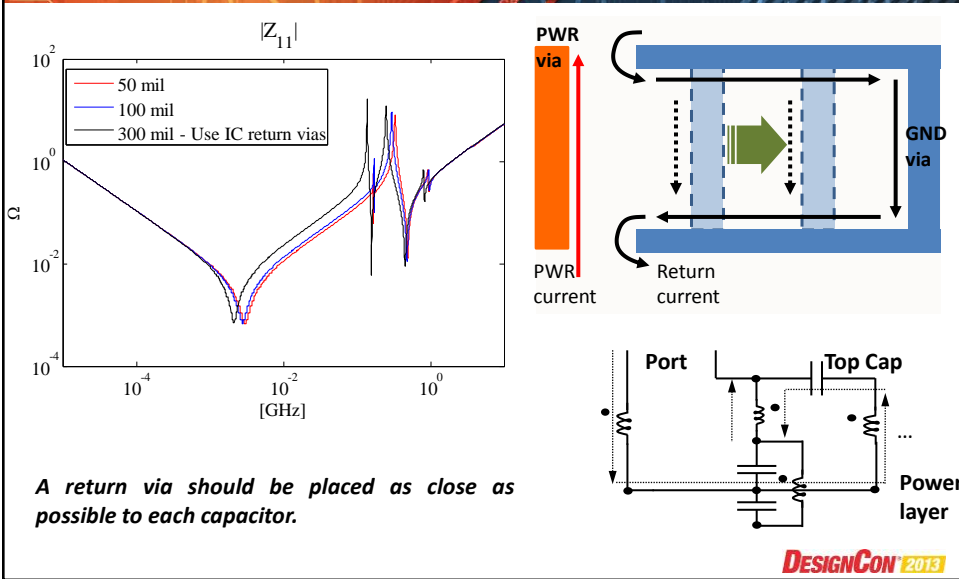
### Case 3 - Distance of Capacitor from IC: Response



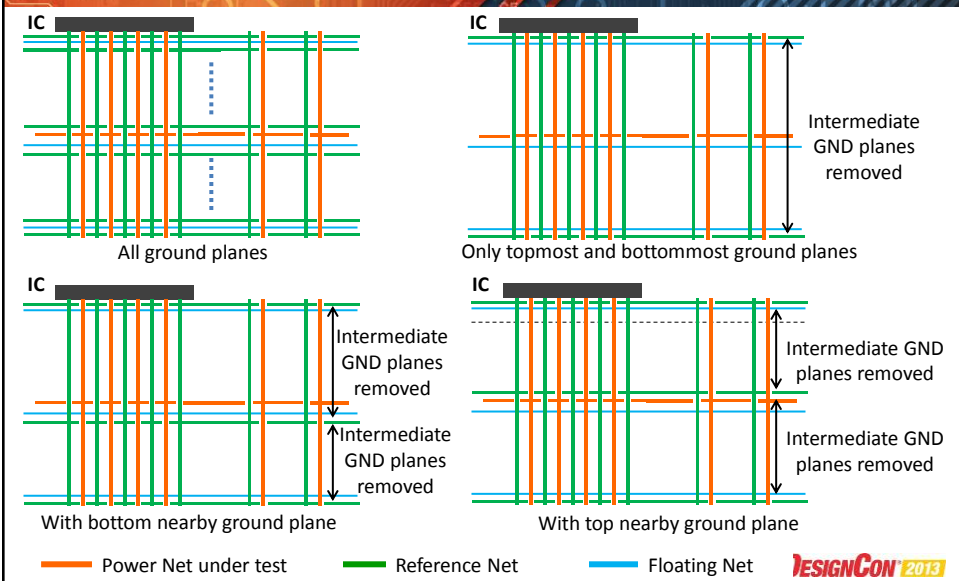
### Case 4 - Distance of Return Via from Capacitor: Geometry



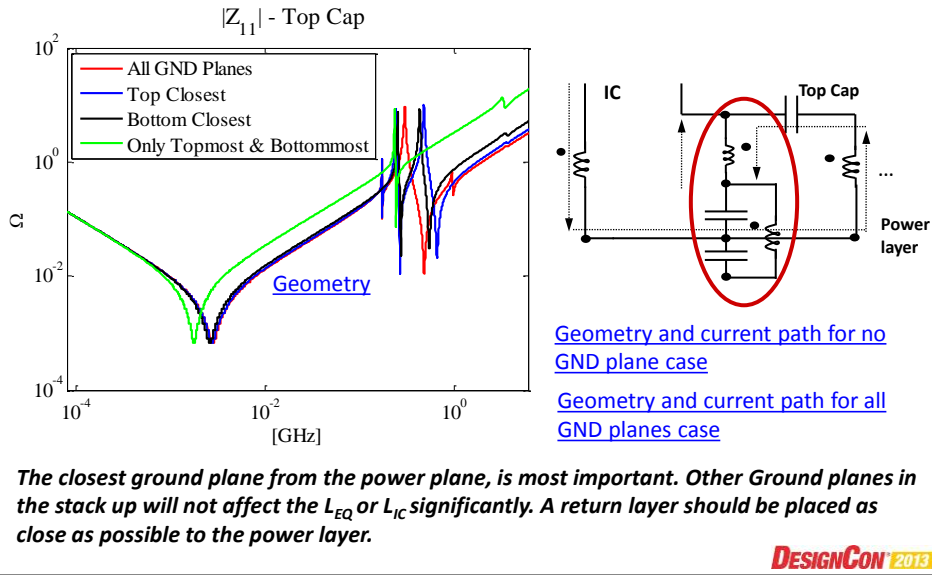
### Case 4 - Distance of Return Via from Capacitor: Response



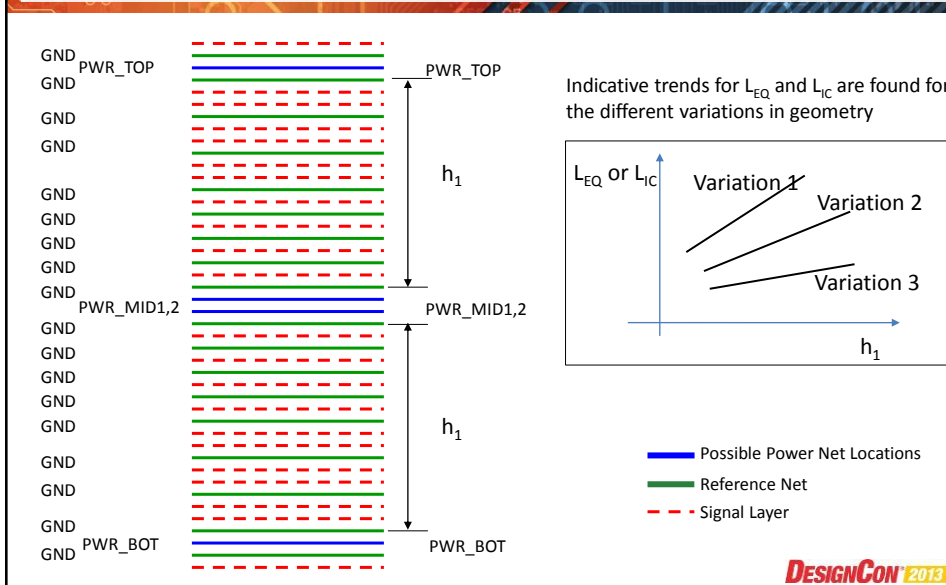
### Case 5 - Distance of Reference Plane from Power Plane: Geometry

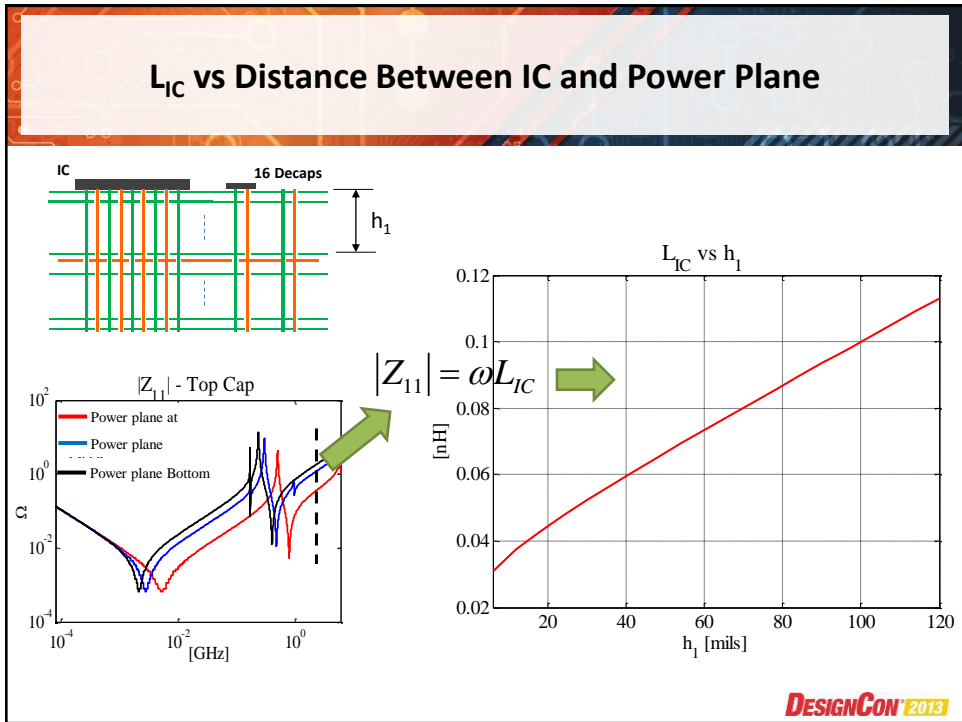
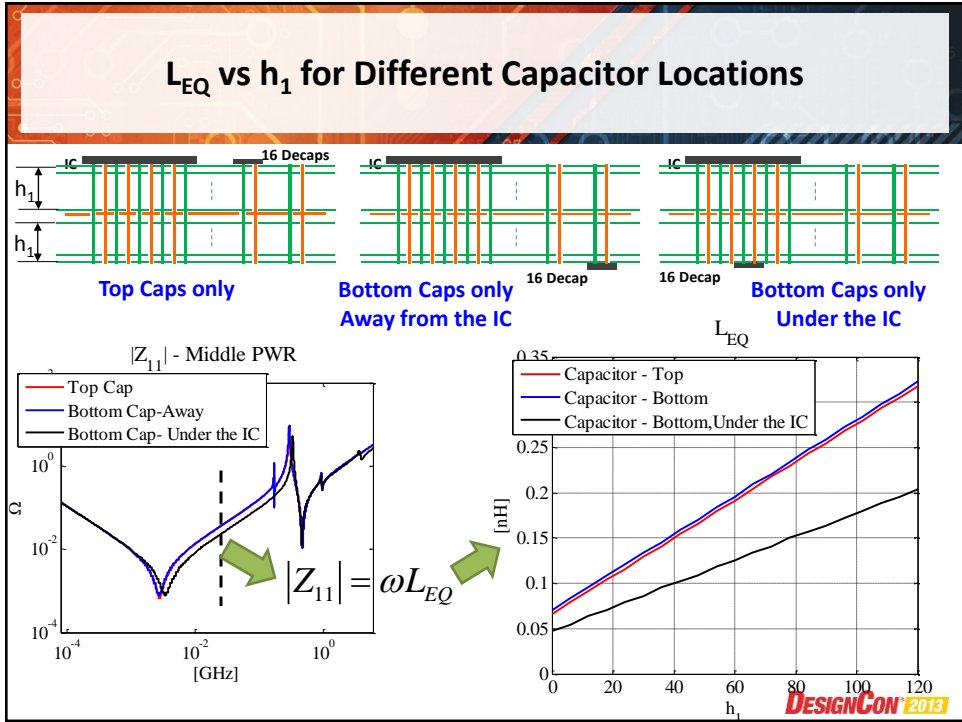


## Case 5 - Distance of Reference Plane from Power Plane: Response



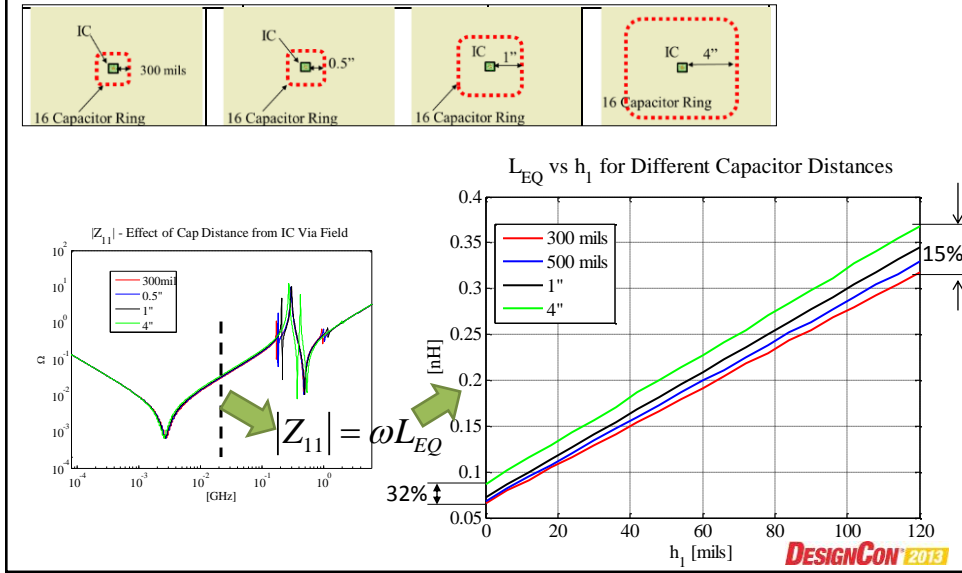
## Trends for $L_{EQ}$ and $L_{IC}$



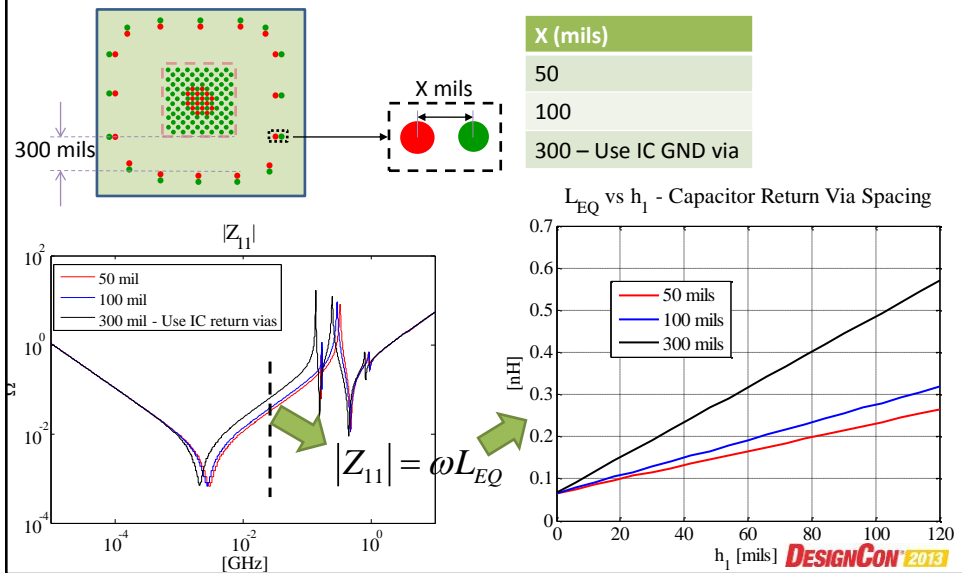




## $L_{EQ}$ vs $h_1$ for Different Capacitor Distances from IC



## $L_{EQ}$ vs $h_1$ for Different Capacitor Return Via Spacing



## Conclusions

- The case study demonstrates an innovative principle behind the guidelines, to lower the input impedance of PDN by lowering the  $L_{EQ}$  and  $L_{IC}$ .
- The guidelines show a process to minimize the  $L_{IC}$  and  $L_{EQ}$  during the layout phase.  $L_{IC}$  being the lowest value that  $L_{EQ}$  can achieve, it  $L_{IC}$  should be minimized at first.
  - The power plane should be placed closest to IC to achieve lowest  $L_{IC}$  and capacitors should be placed closest to the power planes, for a low  $L_{EQ}$ .
  - A return plane should be placed as close as possible to the power plane in the PCB stack up, to lower the inductance contribution from the planes to the  $L_{EQ}$ .
  - A return via should be placed as close as possible to every capacitor power via.
  - The capacitors should be placed around the IC as close as possible to it, when the distance between the capacitor and power planes is small. In thick boards with thin power cavities, the distance of capacitors from the IC will not significantly affect the results.
- Trends provide an intuition for comparative rate of increase in the  $L_{IC}$  and  $L_{EQ}$  values for different layout geometry aspects. This helps to make tradeoffs when layout is for multiple power nets sharing limited resources.

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Thank You

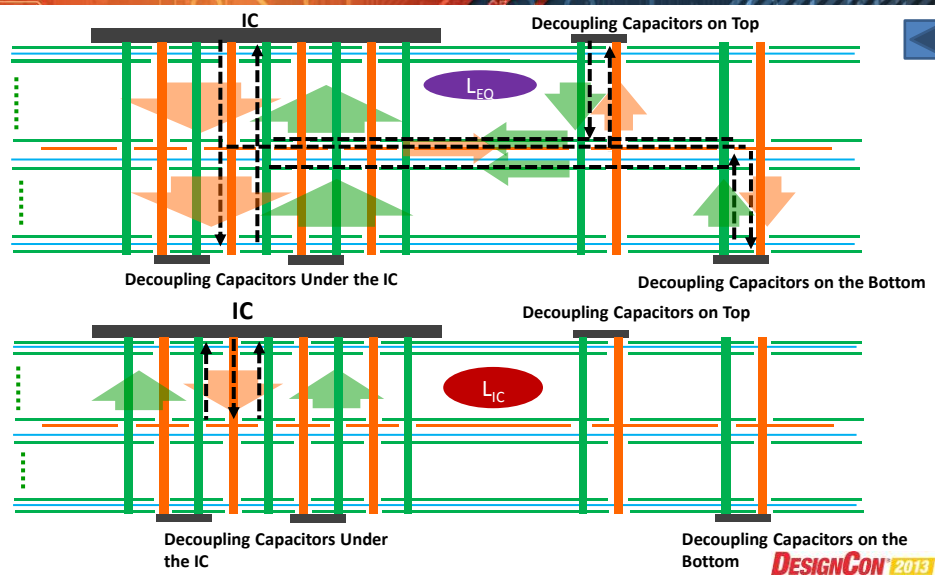
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## References

- [1] "International Technology Roadmap on Semiconductors," ed. [www.itrs.net](http://www.itrs.net).
- [2] M. Swaminathan, J. Kim, I. Novak, and J. P. Libous, "Power distribution networks for system-on-package: status and challenges," *Advanced Packaging, IEEE Transactions on*, vol. 27, pp. 286-300, 2004.
- [3] J. Park, J. Lee, H. Kim, and J. Kim, "Prediction and verification of power/ground plane edge radiation excited by through-hole signal via based on balanced TLM and via coupling model," in *Electrical Performance of Electronic Packaging, 2003*, 2003, pp. 181-184.
- [4] L. D. Smith, R. E. Anderson, D. W. Forehand, T. J. Pelc, and T. Roy, "Power distribution system design methodology and capacitor selection for modern CMOS technology," *Advanced Packaging, IEEE Transactions on*, vol. 22, pp. 284-291, 1999.
- [5] Jinguok Kim; Songping Wu; Hanfeng Wang; Takita, Y.; Takeuchi, H.; Araki, K.; Gang Feng; Jun Fan; , "Improved target impedance and IC transient current measurement for power distribution network design," *Electromagnetic Compatibility (EMC), 2010 IEEE International Symposium on* , vol., no., pp.445-450, 25-30 July 2010.
- [6] Y. Lo, D. Solomon, and W. Richards, "Theory and experiment on microstrip antennas," *Antennas and Propagation, IEEE Transactions on*, vol. 27, pp. 137-145, 1979.
- [7] J. Kim, K. Shringarpure, J. Fan, J. Kim, and J. L. Drewniak, "Equivalent Circuit Model for Power Bus Design in Multi-Layer PCBs With Via Arrays," *Microwave and Wireless Components Letters, IEEE*, vol. 21, pp. 62-64, 2011.
- [8] K. Shringarpure, S. Pan, J. Kim, B. Achkir, B. Archambeault, J. Fan, J. Drewniak, "Lumped Circuit Modeling and Analysis of the Power Distribution Network in a Production Level Multi-layered Printed Circuit Board", [To Be Published].
- [9] Archambeault, B.; Jinguok Kim; Connor, S.; Jun Fan; , "Optimizing decoupling capacitor placement to reduce effective inductance," *Electromagnetic Compatibility (EMC), 2011 IEEE International Symposium on* , vol., no., pp.179-183, 14-19 Aug. 2011

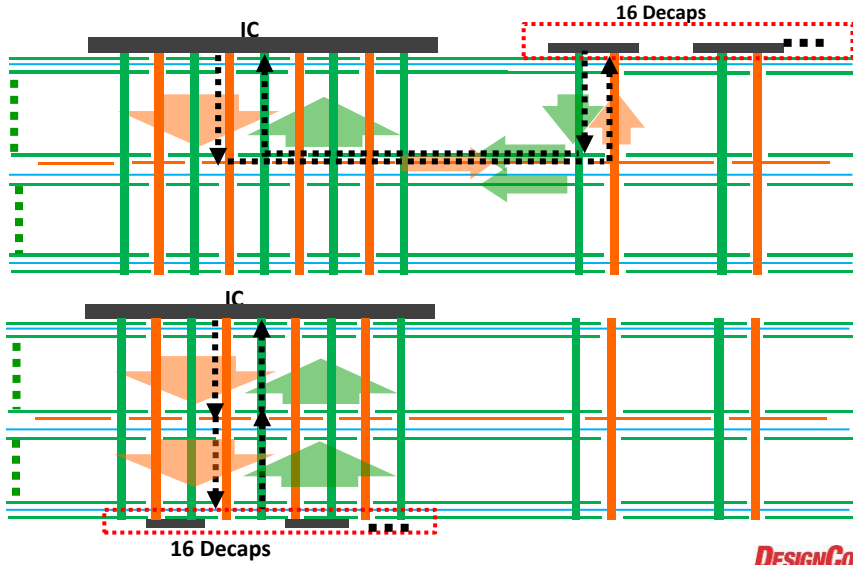
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## Current Paths for $L_{EQ}$ and $L_{IC}$



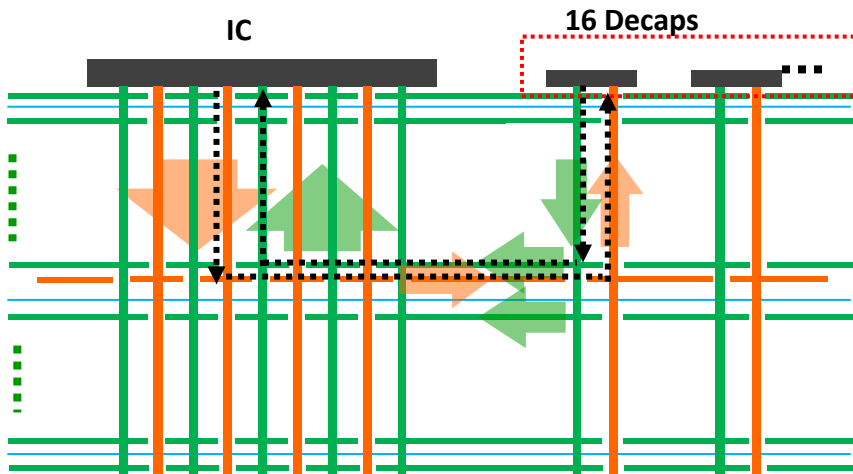
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### Physics – Mid PWR Layer – Top Cap vs Cap sharing IC vias



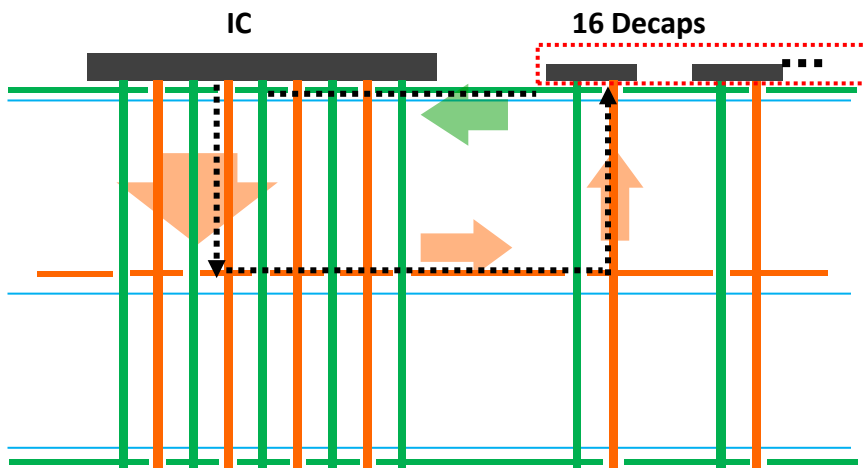
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### Reference Plane Distance – Current Path for All Reference Planes Present



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### Reference Plane Distance – Current Path for No Close Reference Planes



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